

**Search Notes**

Application/Control No.

10/541,237

Examiner

Jean F. Duverne

Applicant(s)/Patent under  
Reexamination

FUJITA ET AL.

Art Unit

2839

**SEARCHED**

Class	Subclass	Date	Examiner
439	630	10/1/2006	JFD
	632		
	61-66		
	632		
	630		
	67		
	593	10/1/2006	JFD

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR